

2008年微电子学研究所发表的 的学术论文

一、CAD技术研究室

- [1] Tao Li and Zhiping Yu, "Full-Chip Leakage Verification for Manufacturing Considering Process Variations," 9th *International Symposium on Quality Electronic Design (ISQED)*, San Jose, March 17-19, 2008.
- [2] Lei Zhang, Xiangqing He, and Zhiping Yu, "A Statistical Characterization of CMOS Process Fluctuations in Subthreshold Current Mirrors," 9th *International Symposium on Quality Electronic Design (ISQED)*, San Jose, March 17-19, 2008.
- [3] Zhidong Chen, Ming Zhang, Ximeng Guan, Jinyu Zhang, and Zhiping Yu, "Real- and mode-space simulation of electron transport in metallic carbon nanotubes using NEGF," *IEEE Int'l Nanoelectronics Conf. (INEC)*, Shanghai, March 24-27, 2008.